Search N	otes

Application/Control No.	Applicant(s)/Patent unde Reexamination	er
10/082,980	CHAPIN ET AL.	
Examiner	Art Unit	
Athanasios Tom Papanikolaou	2625	

SEARCHED				
Class	Subclass	Date	Examiner	
358	Subclass 4.15 1.14 1.13 1.1 1.9 437 439 1-12 31-34 223-232	9/6/06		

Class	Subclass	Date	Examine
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Searched EAST (see attatched search history)	3/21/2006	AP	
Searched EAST (see attatched search history)	3/23/2006	AP	
Searched EAST (see attatched search history) NPL (IEEE) East Search	3/24/2006 9/6/05 1/	AP Self	